

## N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
30	0.010 at V <sub>GS</sub> = 10 V	30	26.5 nC			
30	0.018 at V <sub>GS</sub> = 4.5 V	25	20.5 110			

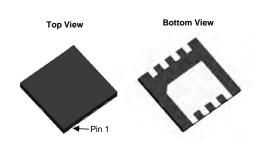
### **FEATURES**

- · Halogen-free
- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested

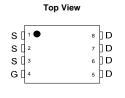


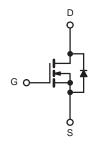
### **APPLICATIONS**

- DC/DC Conversion
  - Low-Side Switch
- Notebook PC
- Gaming



DFN 3x3 EP





N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	V
	T <sub>C</sub> = 25 °C		30	
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	$T_C = 70  ^{\circ}C$	I <sub>D</sub>	22.6	
Continuous Diam Current (1) = 130 C)	T <sub>A</sub> = 25 °C	υ.υ	21.5 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		17.1 <sup>b, c</sup>	Α
Pulsed Drain Current		I <sub>DM</sub>	100	^
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I_	13	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	ls –	3.1 <sup>b, c</sup>	
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	10	
Avalanche Energy	L = 0.111111	E <sub>AS</sub>	5	mJ
	T <sub>C</sub> = 25 °C		16.7	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	10.7	W
Maximum i ower bissipation	T <sub>A</sub> = 25 °C	ט' [	3.7 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		2.4 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	$R_{thJA}$	27	34	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	6	7.5	C/ V V	

#### Notes

- a. Based on  $T_C = 25$  °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 85 °C/W.



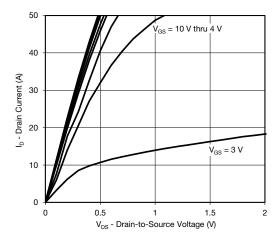
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 uA		27		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I <sub>D</sub> = 250 μA		- 5.6			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Cata Valta da Brain Comunit	1	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A		0.010		Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 10 A		0.018			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A		75		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			650		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		236			
Reverse Transfer Capacitance	C <sub>rss</sub>			20			
Total Cata Chausa		V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		10	20	20 9 nC	
Total Gate Charge	Qg			4.5	9		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		2.1			
Gate-Drain Charge	$Q_{gd}$			0.7			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.2	1.1	2.2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			8	16		
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		16	30		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		17	35		
Fall Time	t <sub>f</sub>			7	15		
Turn-On Delay Time	t <sub>d(on)</sub>			14	30	ns -	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		50	100		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	30		
Fall Time	t <sub>f</sub>			8	18		
Drain-Source Body Diode Characteristi	cs			•			
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			13	_	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				100	Α	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 3 A			1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>				40	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 40 A 41/4 400 A/2 T 0500			20	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		12.5			
Reverse Recovery Rise Time	t <sub>b</sub>	1		7.5		ns	

#### Notes:

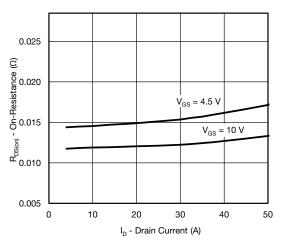
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

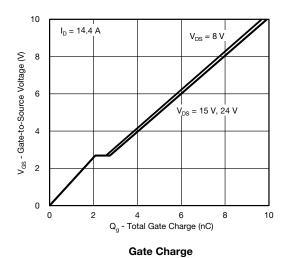


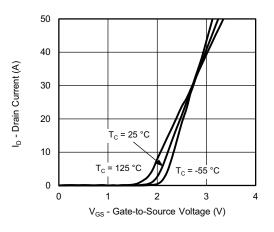


### **Output Characteristics**

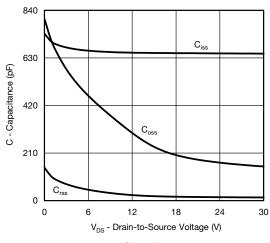


On-Resistance vs. Drain Current

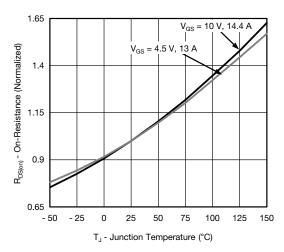




**Transfer Characteristics** 

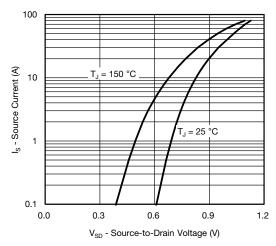


Capacitance

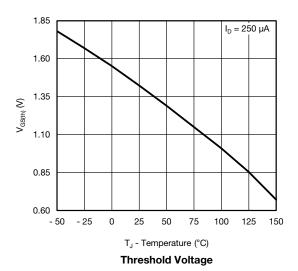


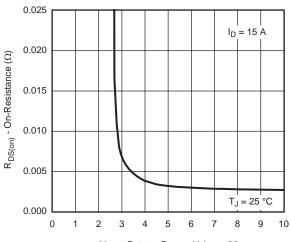
On-Resistance vs. Junction Temperature



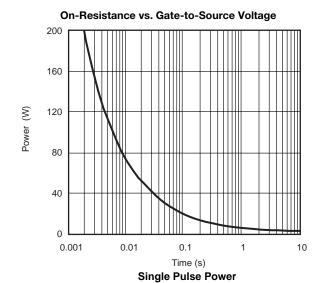


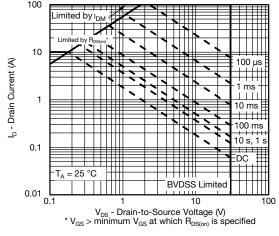
#### Source-Drain Diode Forward Voltage





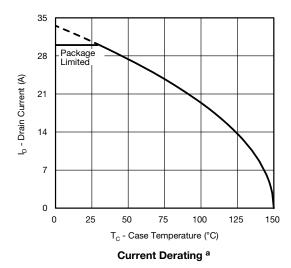
V<sub>GS</sub> - Gate-to-Source Voltage (V)

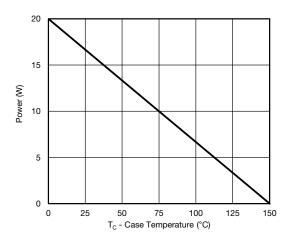




Safe Operating Area, Junction-to-Ambient





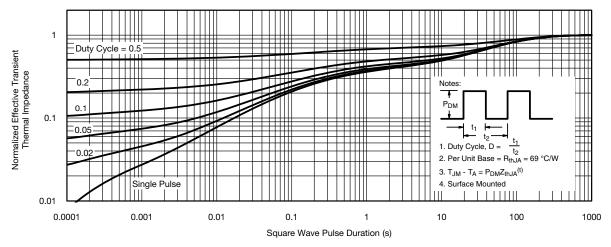


Power, Junction-to-Case

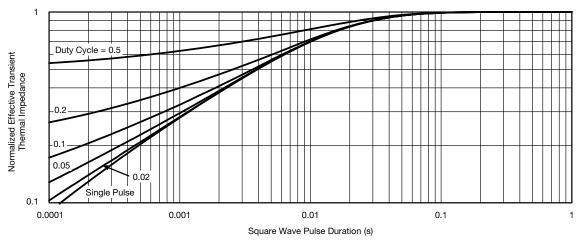
#### Note

a. The power dissipation P<sub>D</sub> is based on T<sub>J</sub> max. = 25 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



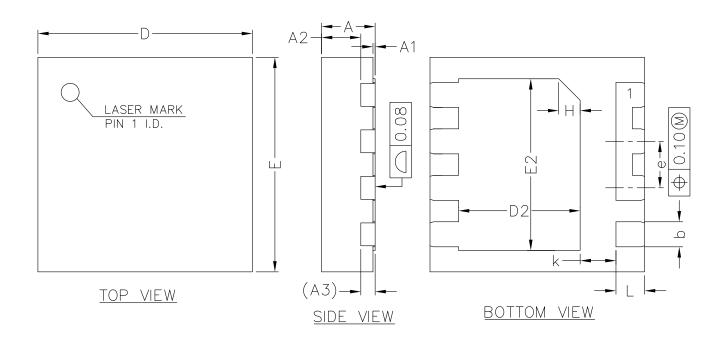


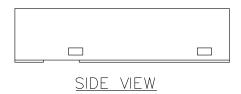
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX		
А	0.70	0.75	0.80		
A1	0.00	0.02	0.05		
A2	0.50	0.55	0.60		
А3	0.20REF				
b	0.30	0.35	0.40		
D	2.90	3.00	3.10		
E	2.90	3.00	3.10		
D2	1.60	1.70	1.80		
E2	2.30	2.40	2.50		
е	0.55	0.65	0.75		
K	0.40	0.50	0.60		
L	0.35	0.40	0.45		



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